

Search Notes

Application/Control No.

10/695,286

Examiner

Ba Huynh

Applicant(s)/Patent under
Reexamination

ITAKURA ET AL.

Art Unit

2179

SEARCHED

Class	Subclass	Date	Examiner
715	705-711	8/5/2007	HB
	772,774		
	778,790		
	791,794		
	796,805		
	808,809		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: USpat, Epo, Jpo, Derwent, IBM- tdb files searched	8/5/2007	HB